

A3LSMS911JPN	FCC ID:
02/06/2023	Date:
KDB 680106 D01 v03r01	Test Procedure:

		10% Battery	50% Battery	70% Battery	
Load	E Measurements (V/m)	Distance from probe (cm)	Distance from probe (cm)	Distance from probe (cm)	Limit (V/m)
		15	15	15	
	A (Bottom)	0.209	0.215	0.206	614.00
	B (Right)	0.245	0.256	0.249	614.00
Phone	C (Top)	0.237	0.226	0.218	614.00
Phone	D (Left)	0.245	0.256	0.256	614.00
	E (Front)	0.594	0.623	0.613	614.00
	F (Back)	0.642	0.642	0.704	614.00

Table 1. E-field Measurement by battery level (phone load)

Load	E Measurements (V/m)	Distance from probe (cm)	Limit (V/m)
	, ,	15	
Watch	F (Back)	0.472	614.00
Earbuds	F (Back)	2.139	614.00

Table 2. E-field Measurement by battery level (non-phone loads)

		10% Battery	50% Battery	70% Battery	
Load	H Measurements (A/m)	Distance from probe (cm)	Distance from probe (cm)	Distance from probe (cm)	Limit (A/m)
		15	15	15	
	A (Bottom)	0.058	0.056	0.056	1.63
	B (Right)	0.066	0.051	0.056	1.63
Phone	C (Top)	0.063	0.058	0.058	1.63
Phone	D (Left)	0.051	0.051	0.056	1.63
	E (Front)	0.056	0.056	0.056	1.63
	F (Back)	0.074	0.056	0.056	1.63

Table 3. H-field Measurement by battery level (phone load)

Load	H Measurements (A/m)	Distance from probe (cm)	Limit (A/m)	
		15		
Watch	F (Back)	0.078	1.63	
Earbuds	F (Back)	0.169	1.63	

Table 4. H-field Measurement by battery level (non-phone loads)

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А	В	С	D	Е	F
BOTTOM EDGE	RIGHT EDGE	TOP EDGE	LEFT EDGE	FRONT (SCREEN)	BACK

Table 5. EUT Position Description

Note:

- The right and left edge are determined with the EUT screen facing the user.
- 2. H-Field Measurements were found to be noise floor

Description of Test Setup

- Testing was performed with a calibrated field probe.
- Measurement was performed on each side of the EUT as described in Table 5.
- Testing was performed at the distances and different battery levels as indicated on Tables 1 through 4.
- Measurement procedure was performed per FCC Guidance.

Test Equipment

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
Narda	EHP-200AC	Electronic & Magnetic Field Probe	6/9/2022	Annual	6/9/2023	170WX70211

Table 6. Test Equipment

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